PCN Number: 20		202	2009	00924004.1			PC	<b>PCN Date:</b> Oct. 1, 2020		Oct. 1, 2020	
Title: Qualification of F		of FF	FAB as an additional Fab site option for select BICMOS13 devices								
Cus	stomer	Contact:		PCN Manager Dept:			Quality Services				
Proposed 1 <sup>st</sup> Ship Date:			:	Jan	n. 1, 2021 Estimated Samp Availability:			le	Date provided at sample request.		
Change Type:											
Assembly Site				Assembly Process			Assembly Materials				
Design				Electrical Specification				Mechanical Specification			
Test Site				Packing/Shipping/Labeling				Test Process			
Wafer Bump Site				Wafer Bump Material				W	Wafer Bump Process		
				Wafer Fab Materials				W	afer F	ab Process	
					Part number change						
	DCN Details										

## **Description of Change:**

Texas Instruments is pleased to announce the qualification of its FFAB fabrication facility as an additional Wafer Fab source for the selected devices listed in the "Product Affected" section.

	<b>Current Sites</b>		Additional Sites		
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter
MAINEFAB	BICMOS13	200 mm	FFAB	BICMOS13	200mm

Qual details are provided in the Qual Data Section.

## **Reason for Change:**

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

## **Changes to product identification resulting from this PCN:**

# Current

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
MAINEFAB	CUA	USA	South Portland

#### **New Fab Site**

Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City
FR-BIP-1	TID	DEU	Freising

Sample product shipping label (not actual product label)

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q: MSL 2 /260C/1 YEAR SEAL DT

MSL 1 /235C/UNLIM 03/29/04

(1P) SN74LS07NSR (D) 0336 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483S12 (20L) CSO: SHE (22L) ASO: MLA (23L) ACO: MYS

OPT: ITEM: 5A (L)T0:1750 LBL:

**Product Affected Group:** 

DS250DF200ABMR	DS250DF800ABVR	DS280MB810ZBLR	LMH1219RTWR
DS250DF200ABMT	DS250DF800ABVT	DS280MB810ZBLT	LMH1219RTWT
DS250DF210ABMR	DS250DF810ABVR	LMH0324RTWR	LMH1226RTWR
DS250DF210ABMT	DS250DF810ABVT	LMH0324RTWT	LMH1226RTWT

DS250DF230ZLSR	DS280BR800ZBFR	LMH0397RTVR	LMH1228RTVR
DS250DF230ZLST	DS280BR800ZBFT	LMH0397RTVT	LMH1228RTVT
DS250DF400ABMR	DS280BR810ZBFR	LMH0604RTWR	LMH1297RTVR
DS250DF400ABMT	DS280BR810ZBFT	LMH0604RTWT	LMH1297RTVT
DS250DF410ABMR	DS280BR820ZBLR	LMH1208RTVR	
DS250DF410ABMT	DS280BR820ZBLT	LMH1208RTVT	

# **Qualification Report** Approve Date 28-July-2020

### Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: LMH1297RTVTR	QBS Process Device: DS280DF810ABWT	QBS Process Reference LMX2581SQENOPB	QBS Package Reference DS110DF1610SFB
ELFR	Early Life Failure Rate, Ta=115C, Tj~160C	48 Hrs	-	-	3/2400/0	-
HTOL	Life Test, Ta=115C, Tj~160C	500 Hrs	-	-	3/231/0	-
HTOL	Life Test, Ta=125C	1000 Hrs	2/154/0	1/77/0	-	-
AC	Autoclave 121C	96 Hrs	-	-	3/231/0	-
HAST	Biased HAST, 130C/85%RH	96 Hrs	-	-	3/231/0	3/231/0
TC	Temperature Cycle, -55/125C	700 Cycles	-	-	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000 Hrs	-	-	3/231/0	3/231/0
HBM	ESD - HBM	2000V	-	1/3/0	3/9/0	-
HBM	ESD – HBM (all pins)	5000V	1/3/0	-	-	-
HBM	ESD - HBM (exclude pins 13, 27, 29)	6000V	1/3/0	-	-	-
CDM	ESD - CDM	1000V	-	1/3/0	-	-
LU	Latch-up	25C	-	1/6/0	3/18/0	-
LU	Latch-up	85C	-	1/6/0	3/18/0	-
LU	Latch-up	125C	1/6/0	-	-	-

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

<sup>-</sup> QBS: Qual By Similarity - Qual Device LMH1297RTVTR is qualified at LEVEL3-260CG

## **Qualification Report** Approve Date 22-April-2020

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: DS280DF810ABWT	QBS Process Device: LMH1297RTVT R	QBS Process Reference LMX2581SQENOPB	QBS Package Reference DS110DF1610SFB
ELFR	Early Life Failure Rate, Ta=115C, Tj~160C	48HRS	-	-	3/2400/0	-
HTOL	Life Test, Ta=115C, Tj~160C	500HRS	-	-	3/231/0	-
HTOL	Life Test, Ta=125C	1000HRS	1/77/0	2/154/0	-	-
AC	Autoclave 121C	96HRS	-	-	3/231/0	-
HAST	Biased HAST, 130C/85%RH	96HRS	-	-	3/231/0	3/231/0
TC	Temperature Cycle, -55/125C	700CYC	-	-	3/231/0	3/231/0
HTSL	High Temp Storage Bake 150C	1000HRS	-	-	3/231/0	3/231/0
HBM	ESD - HBM	2000V	1/3/0	-	3/9/0	-
CDM	ESD - CDM	1000V	1/3/0	-	-	-
LU	Latch-up	25C	1/6/0	-	3/18/0	-
LU	Latch-up	85C	1/60	-	3/18/0	-

- OBS: Qual By Similarity
- Qual Device DS280DF810ABWT is qualified at LEVEL3-260CG
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable The following are equivalent HTOL options based on an activation energy of 0.7 eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For guestions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
WW PCN Team	PCN ww admin team@list.ti.com

#### IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATASHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, or other requirements. These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale (www.ti.com/legal/termsofsale.html) or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision

of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.